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PATENT

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Serial No.: U.S.S.N. 10/697,922

Inventor: Van Steenkiste, et al.

Title: METHOD FOR SECURING CERAMIC STRUCTURES AND FORMING  
ELECTRICAL CONNECTIONS ON THE SAME

Filed: October 30, 2003

Art Unit: 3752

ATTORNEY DOCKET: DP-306458

Examiner: Unknown

**CERTIFICATE OF MAILING**

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Date*Lindsey Diskerson*  
Lindsey Diskerson**STATEMENT ACCOMPANYING  
INFORMATION DISCLOSURE STATEMENT**

Applicant(s) requests the Examiner to consider and make of record the reference(s) and/or information disclosed herein or on the attached PTO 1449.

**CHECK ONE: (A, B, or C.)**

☒ A. This statement is submitted within 1) three months after the filing date (even if after the first action); or 2) within three months of the date of entry of the national stage or 3) before the mailing date of a first Office Action on the merits. No fee or statement is required.

☐ B. This statement is submitted after the period specified in para. A, but before Final Office Action or Notice of Allowance or the close of prosecution.

**CHECK ONE: (1, 2, or 3)**

☐ 1. I hereby state that each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement; or

**U.S.S.N. 10/616,490 (DP-306711) – 2**

☐ 2. I hereby state that no item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the person signing the certification after making reasonable inquiry, no item of information contained in the information disclosure statement was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of the information disclosure statement.

☐ 3. Charge the \$180 fee set forth in 37 CFR §1.17(p) to Delphi Technologies, Inc. Deposit Account No. 50-0831.

☐ C. This statement is submitted after a Final Office Action or Notice of Allowance or the close of prosecution, but before payment of the issue fee. Charge the \$180 fee set forth in 37 CFR §1.17(p) to Delphi Technologies, Inc. Deposit Account No. 50-0831.

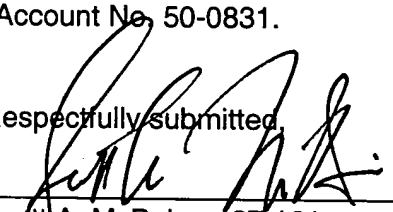
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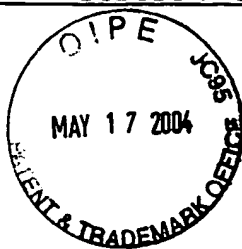
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If any additional fee or any additional amount of fee be required in connection with this Information Disclosure Statement, Applicant respectfully requests that such fee or amount of fee be charged to Delphi Technologies, Inc. Deposit Account No. 50-0831.

Respectfully submitted,

  
\_\_\_\_\_  
Scott A. McBain – 37,181  
Delphi Technologies, Inc.  
Telephone (248) 813-1235

enc: PTO 1449 and references

**INFORMATION DISCLOSURE CITATION WITH DOCUMENT COPIES**

Atty. Docket No. DP-306458	Serial No. 10/697,922
Applicant THOMAS HUBERT VAN STEENKISTE	
Filing Date October 30, 2003	Group 3752

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

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Examiner \_\_\_\_\_ | Date Considered \_\_\_\_\_

**\*Examiner: Initial if reference considered whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.**

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 Examiner

[Date Considered]

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